

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10556457	SEIFERT ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	DEREK S CHAPEL	2872

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
359	359-362, 368, 379-384, 391 (text only)	12/9/2008	DSC
356	244, 246 (text only)	12/9/2008	DSC
600	101, 136-137, 139-150, 164, 172-173 (text only)	12/9/2008	DSC
359	362, 368, 379-384, 391, 499 (text only, see attached)	6/1/2009	DSC
356	244, 246 (text only, see attached)	6/1/2009	DSC
600	101, 136-137, 139-150, 164, 172-173 (text only, see attached)	6/1/2009	DSC

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Consulted with Arnel Lavarias about the search	12/9/2008	DSC

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

/D. S. C./  
Examiner.Art Unit 2872